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Microscopy AND Microanalysis

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45th Annual Meeting of the Microanalysis Society
44th Annual Meeting of the International Metallographic Society

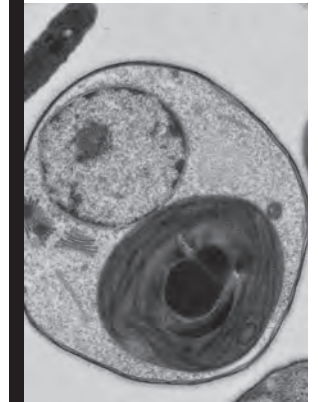
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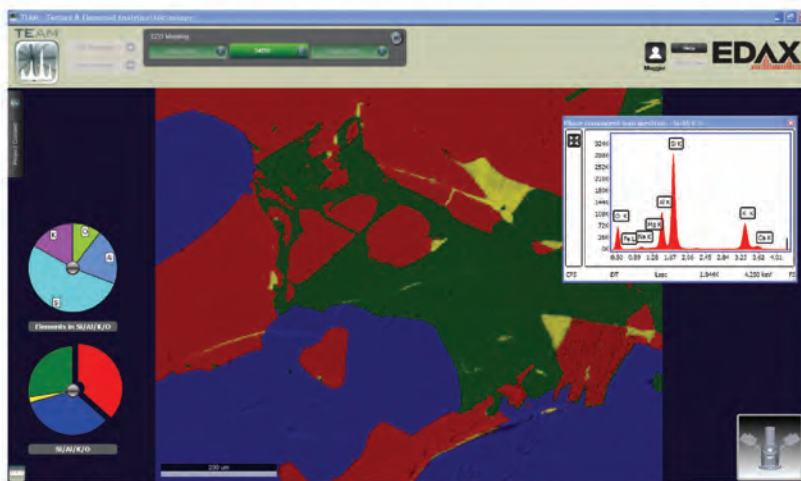
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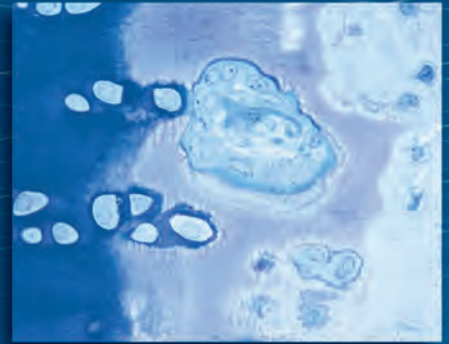
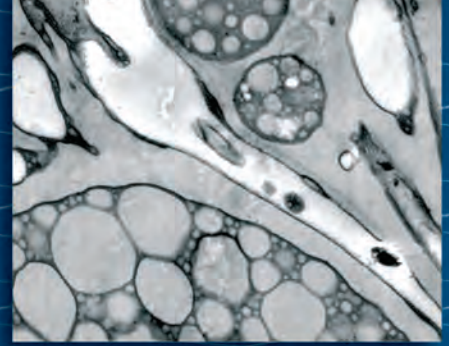
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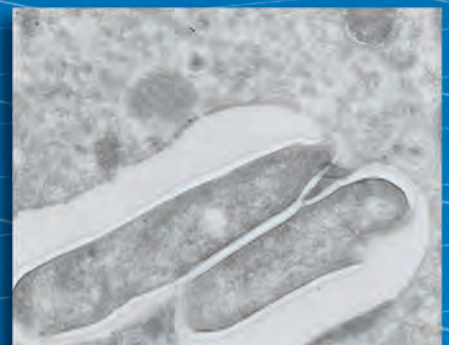
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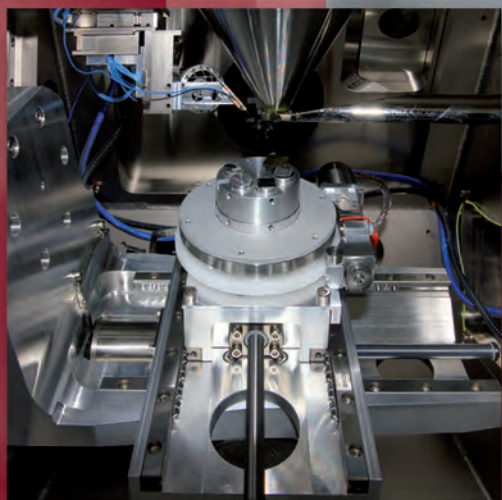
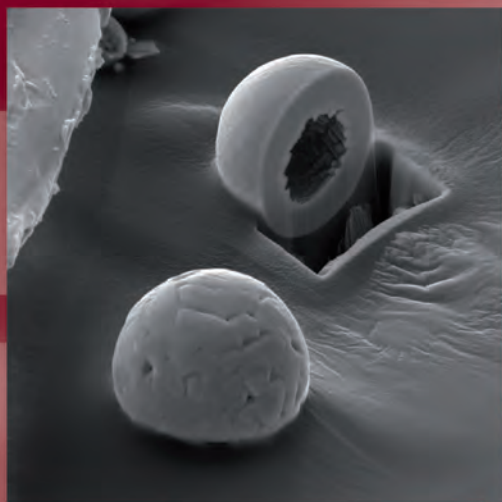
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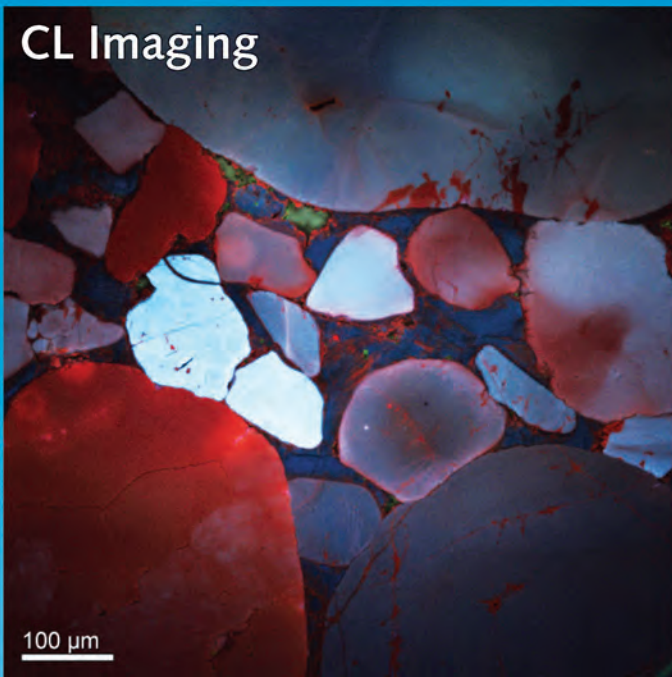
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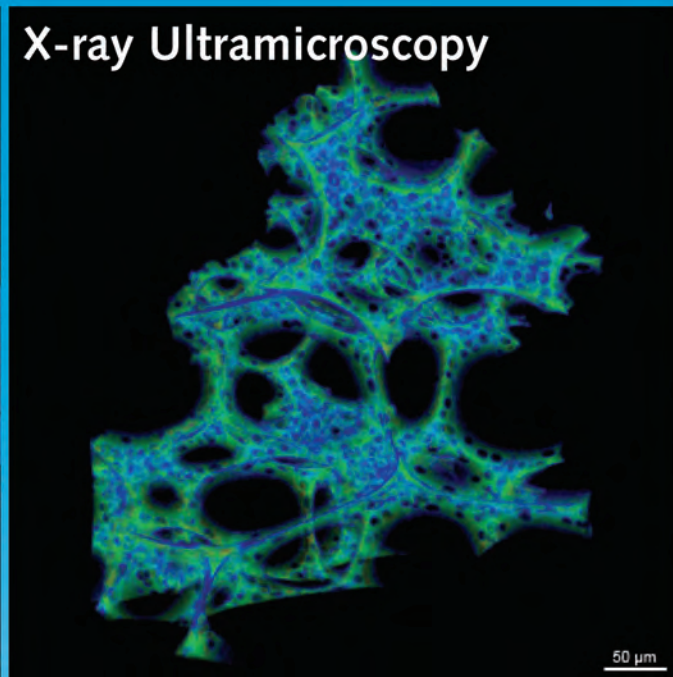
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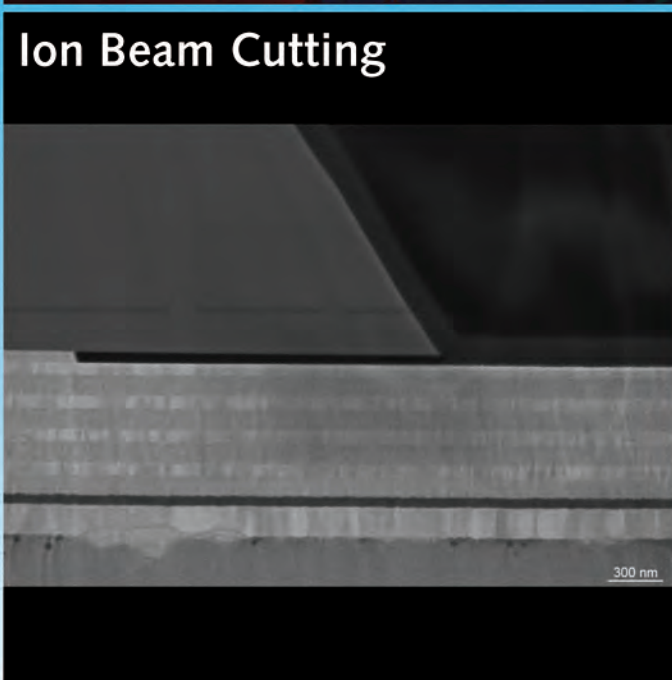
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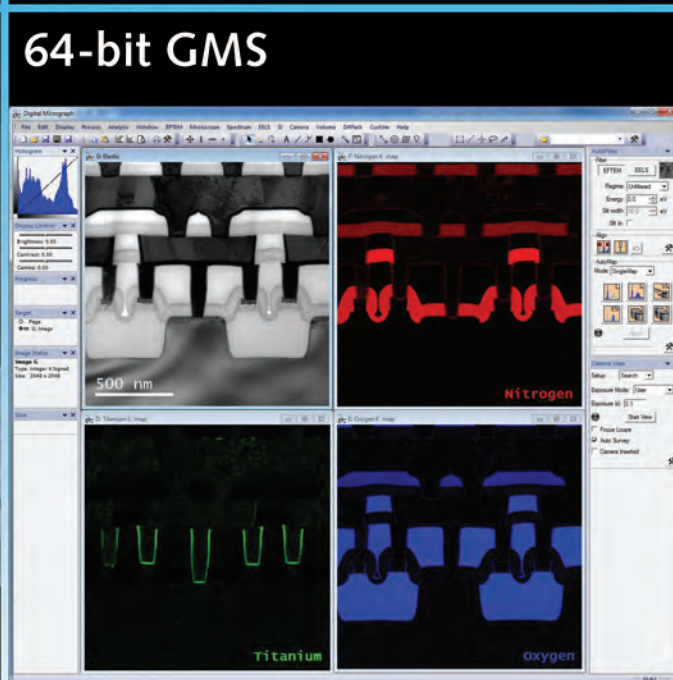
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